

**Notice of References Cited**

Application/Control No.

10/631,928

Applicant(s)/Patent Under

Reexamination

TEOH ET AL.

Examiner

Victor X. Nguyen

Art Unit

3734

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,128,073	10-2006	van der Burg et al.	128/887
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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**FOREIGN PATENT DOCUMENTS**

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